

Compact Modeling at Infineon

MOS-AK in Munich
2018-03-13

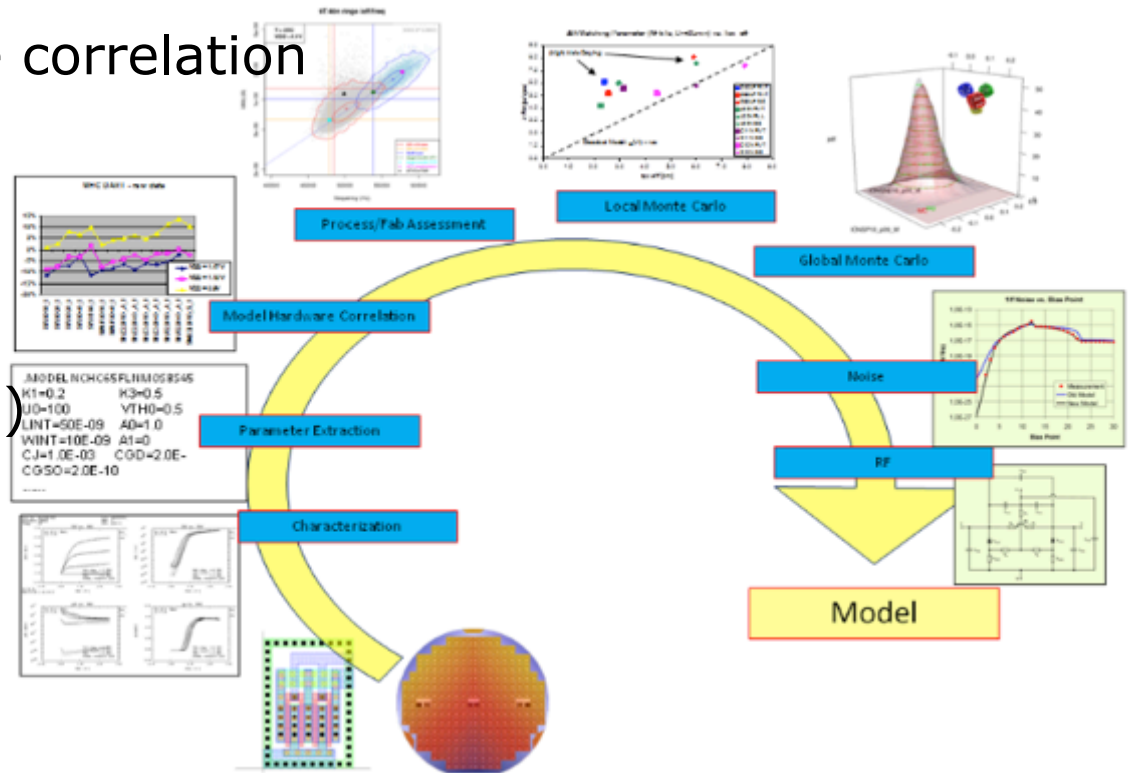
Klaus-Willi Pieper



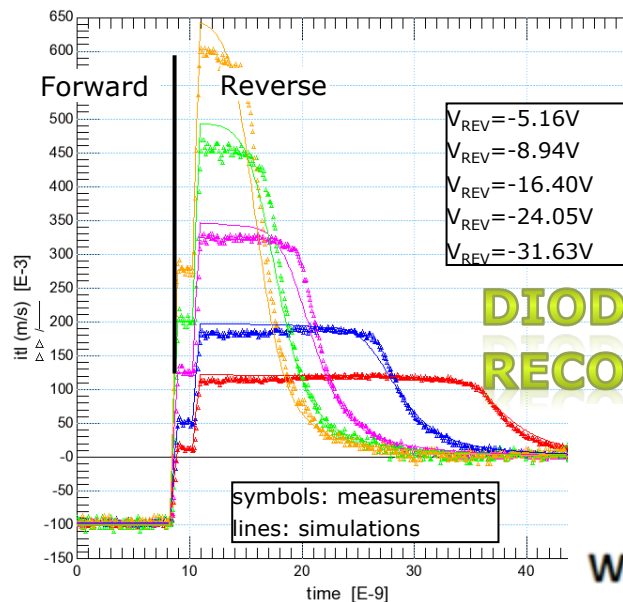
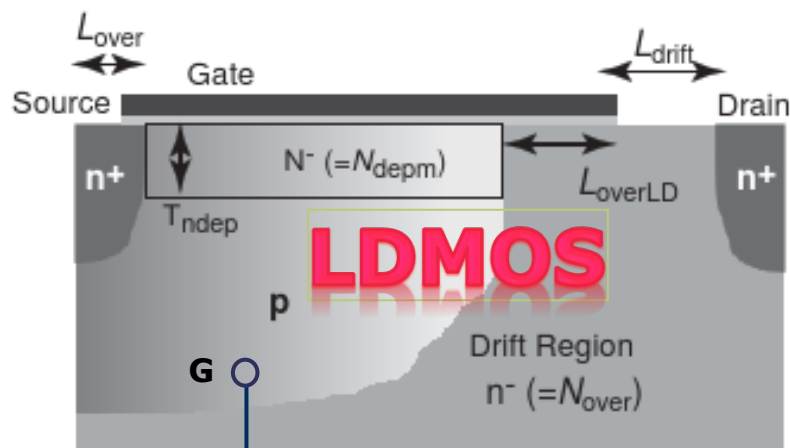
Modeling in Central Department

MDL: Modeling

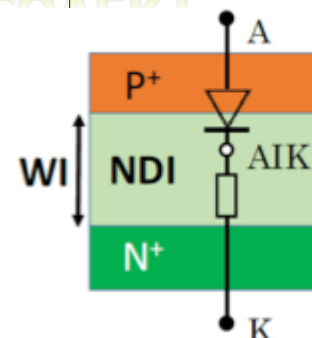
- ✓ Responsible for CMOS incl. embedded flash and RF technologies
- ✓ Technology assessment (together with other departments)
- ✓ Technology target setting (together with other departments)
- ✓ Modeling (nom / variations (MonteCarlo) / corner)
- ✓ MHC = model hardware correlation
- ✓ RF-modeling
- ✓ Noise-parameter
- ✓ BEOL-extraction (metallization parasitics)
- ✓ Preparation for design flow usage



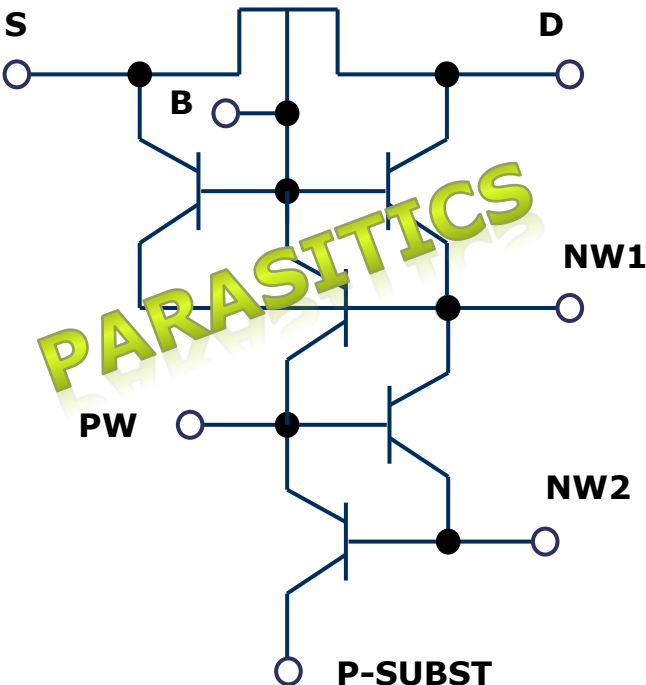
Automotive Power Modeling Group



DIODE REVERSE RECOVERY

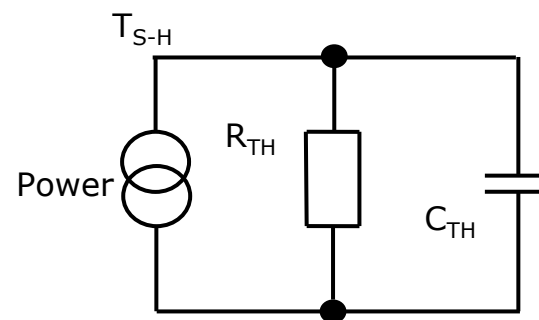


PARASITICS



Compact Models

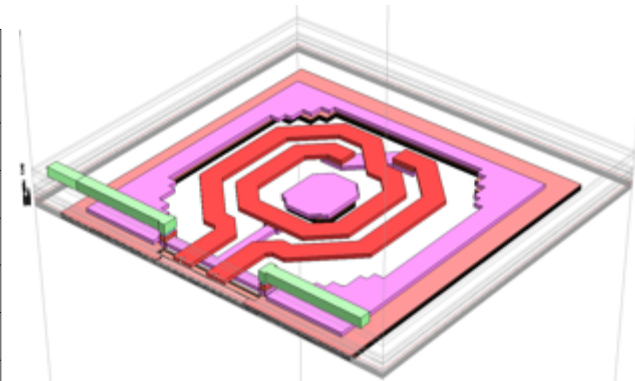
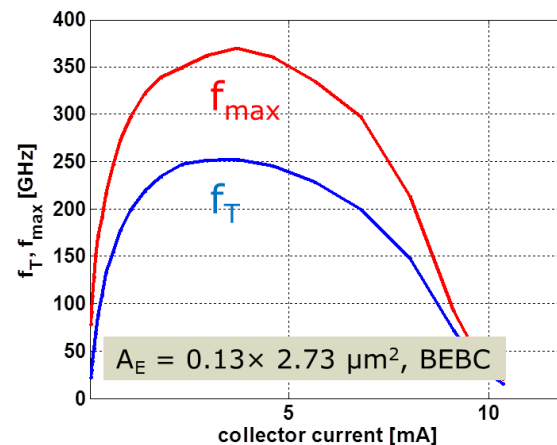
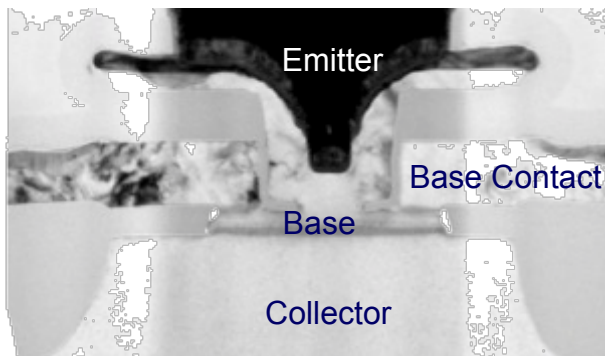
- > HiSIM-HV
- > BSIM3/4/SOI
- > VBIC, BJT
- > JFET
- > Sub-circuits
- > VerilogA Models



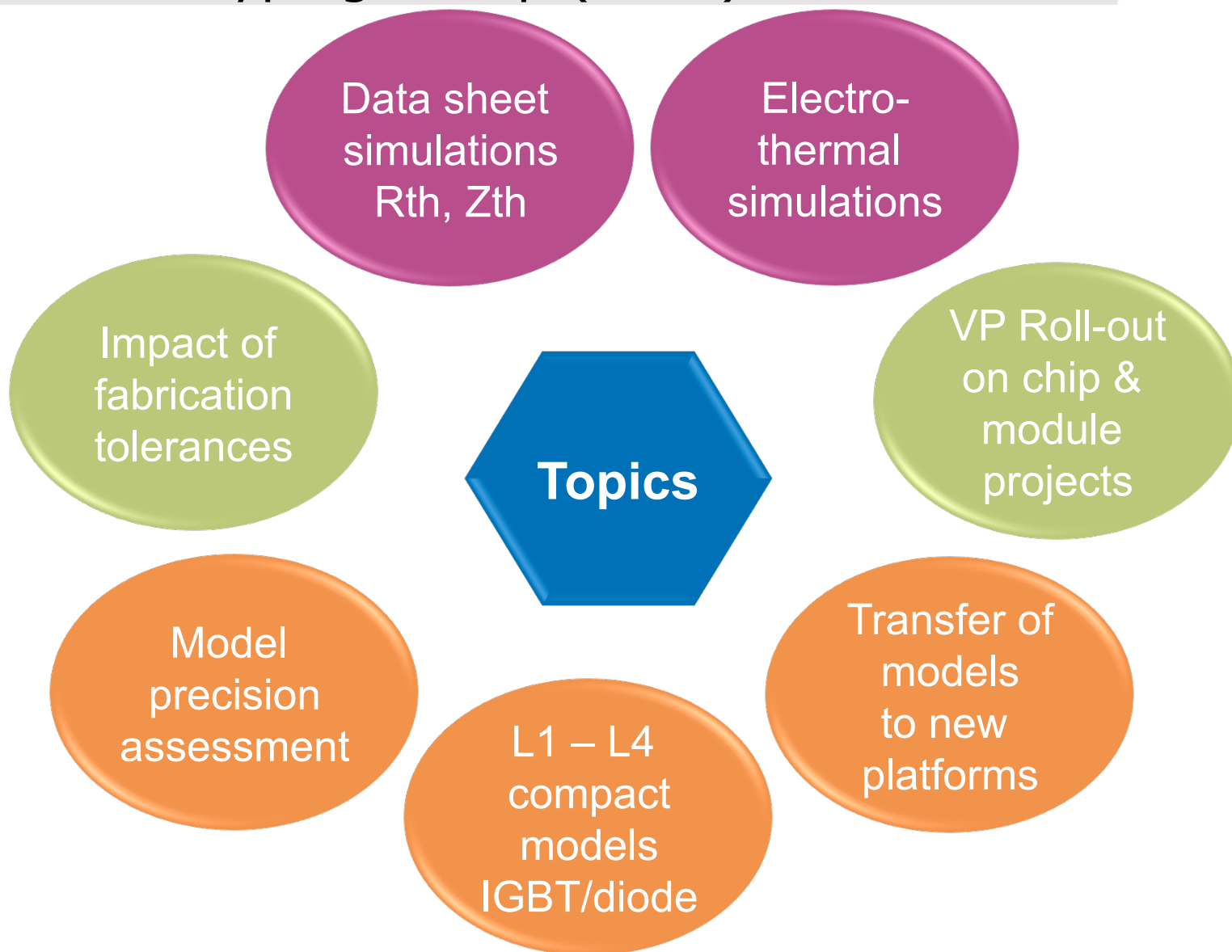
Self-Heating

Autom. S&C Radar Tech. Modeling Group

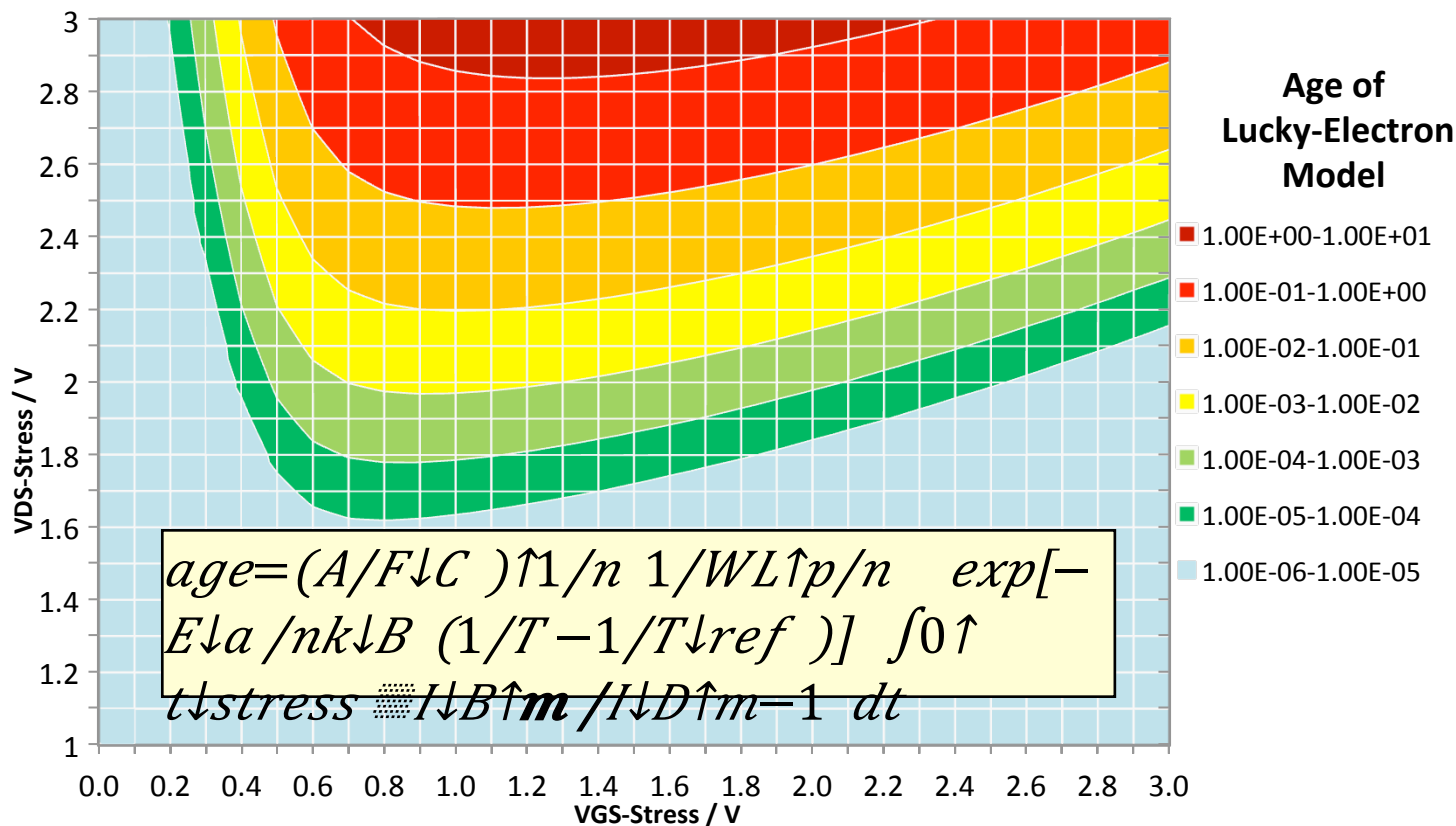
- › In radar technology group, together with technology and RF circuit design experts
- › Topics:
 - Active devices (SiGe HBTs: HICUM, BJT)
 - Passive devices: inductors, transformers, transmission Lines
 - Crosstalk mitigation, RF design methodology



Virtual Prototyping Group (IGBT)



Special Topic: Aging Simulation



CMC workgroup **Reliability Equations** is looking for candidates of aging equations for MOS, LDMOS and Bipolar. Effects like Hot Carrier Injection (HCI), Bias Temperature Instability (BTI), etc.



Part of your life. Part of tomorrow.

